Measurement of off-shell Higgs boson

## production in the $H \rightarrow ZZ \rightarrow 4\ell$ decay channel

using Neural Simulation-Based Inference

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https://indico.cern.ch/e/higgs2024



# Introduction

#### **Off-shell** $H \rightarrow ZZ$

- First evidence for production in 2022 [<u>ATLAS</u>, <u>CMS</u>]
- Small signal, most visible in  $H \rightarrow VV$ , due to enhanced cross-section from V-bosons in the decay channel and *t*-quarks in the quark loop going on-shell.





Off-shell Higgs signal (S) strongly interferes (S+I) with background (gg bkg.) and thus cannot be measured independently.



Interfering background

# The off-shell Higgs boson

The probability model of the off-shell Higgs boson:

$$p(x \mid \mu) = \frac{1}{\nu(\mu)} \begin{bmatrix} \mu \cdot \nu_{S} \cdot p_{S}(x) + \sqrt{\mu} \cdot \nu_{I} \cdot p_{I}(x) + \nu_{B} \cdot p_{B}(x) + \nu_{NI} \cdot p_{NI}(x) \end{bmatrix}$$

$$\nu \rightarrow \text{Exp events}$$

$$p_{S}(x)$$

$$p_{I}(x) = 2 \cdot Re \begin{bmatrix} s & p_{S}(x) & p_{B}(x) \\ s & p_{S}(x) & p_{B}(x) \\ ggF \text{ Signal} & ggF \text{ Background} \end{bmatrix}$$
We aim to measure the off-shell signal strength  $\mu = \frac{\sigma_{obs}^{H \rightarrow ZZ \rightarrow 4\ell}}{\sigma_{ebp}^{H \rightarrow ZZ \rightarrow 4\ell}}$ 



Standard Signal vs Background classification



Binned Poisson Likelihood fit is performed



Signal vs Background discriminant optimal ONLY when signal **linearly** scales with parameter.

 $= \mu \cdot \frac{p_S(x)}{p_B(x)} + \frac{p_B(x)}{p_B(x)}$  $p(x \mid \mu)$ Neyman pearson lemma i.e. maximally optimal across the parameter range



Standard Signal vs Background classification



$$D_{NN} = \frac{1}{p_B + 0.1 \cdot p_{NI}}$$

Standard Signal vs Background classification

Signal vs Background discriminant optimal ONLY when signal **linearly** scales with parameter.

$$\frac{p(x \mid \mu)}{p_B(x)} = \mu \cdot \frac{p_S(x)}{p_B(x)} + \frac{p_B(x)}{p_B(x)}$$
Neyman pearson

But what if there is large non-linearity?

# E.g.: interference effects of off-shell Higgs boson production.

$$\frac{p(x \mid \mu)}{p_B(x)} = \mu \cdot \frac{p_S(x)}{p_B(x)} + \sqrt{\mu} \cdot \frac{p_I(x)}{p_B(x)} + \frac{p_B(x)}{p_B(x)}$$

What about optimally discriminating interference from background?

6

1



$$\mathcal{D}_{NN} = \frac{PS}{p_B + 0.1 \cdot p_{NI}}$$

Standard Signal vs Background classification

Signal vs Background discriminant optimal ONLY when signal **linearly** scales with parameter.

$$\frac{p(x \mid \mu)}{p_B(x)} = \mu \cdot \frac{p_S(x)}{p_B(x)} + \frac{p_B(x)}{p_B(x)}$$
Neyman pearson  
lemma

But what if there is large non-linearity?

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Standard Signal vs Background classification



Data / Exp.

## **New Measurement**

Carefully trained parameterized per-event density ratios are now used to build the test statistic:



 $t_{\mu}$ 

Note: we use the same pre-selections, Monte Carlo samples, background normalization, and systematic uncertainty model as the previously published analysis [link to paper for details]

## **New Measurement**

Carefully trained parameterized per-event density ratios are now used to build the test statistic:



**ATLAS** Preliminary  $\sqrt{s} = 13$  TeV, 140 fb<sup>-1</sup>

 $4\ell$  only

**Obs NSBI** 

Exp NSBI

**Obs Histogram** 

Exp Histogram

3.0

Exploiting the known analytical formula - we break down the parameterized ratio into simpler parts:

 $t_{\mu}$ 

12

10

8

$$\frac{p(x \mid \mu)}{p(x \mid \hat{\mu})} = \frac{p(x \mid \mu) / p_{ref}(x)}{p(x \mid \hat{\mu}) / p_{ref}(x)} \longrightarrow \frac{p(x \mid \mu)}{p_{ref}(x)} = \mu \cdot \frac{p_S(x)}{p_{ref}(x)} + \sqrt{\mu} \cdot \frac{p_I(x)}{p_{ref}(x)} + \frac{p_B(x)}{p_{ref}(x)} + \frac{p_{NI}(x)}{p_{ref}(x)} + \frac{p_{NI}(x)}{p_{ref$$

 $p_{ref}$  is a carefully chosen **parameter**independent hypothesis

We learn everything, including interference effects

## **Overview: Neural Simulation-Based Inference**

Full test statistic function with nuisance parameters  $\alpha$ :

$$t(\mu) = -2 \cdot \log \frac{\mathsf{Pois}(N_{obs} | \mu, \hat{\alpha})}{\mathsf{Pois}(N_{obs} | \hat{\mu}, \hat{\alpha})} - 2 \cdot \sum_{i=1}^{N_{obs}} \log \frac{p(x_i | \mu, \hat{\alpha}) / p_{ref}(x_i)}{p(x_i | \hat{\mu}, \hat{\alpha}) / p_{ref}(x_i)} - 2 \cdot \sum_{k}^{N_{syst}} \log \frac{L_{subs}(\hat{\alpha})}{L_{subs}(\hat{\alpha})}$$
  
Extended Sum of event-by-event

Poisson term

Sum of event-by-event log-likelihood ratios

Constraint terms

$$N_{obs} \rightarrow$$
 total observed events

 $L_{subs} \rightarrow$  likelihood from subsidiary measurements of the nuisance parameters

## **Overview: Neural Simulation-Based Inference**

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$$parameter-independent ratio$$

$$\frac{p(x_i | \mu, \alpha)}{p_{ref}(x_i)} = \frac{1}{\sum_{c} G_c(\alpha) \cdot f_c(\mu) \cdot \nu_c} \sum_{c} \left[ f_c(\mu) \cdot g_c(x_i | \alpha) \cdot \nu_c \cdot \frac{p_c(x_i)}{p_{ref}(x_i)} \right]$$
Parameterized per-event ratios
$$parameter \text{ dependancies are factorized out (see slide 10)} \qquad g_c(x | \alpha) = \prod_{m} \frac{p_c(x | \alpha_m)}{p_c(x)}$$

## **Overview: Neural Simulation-Based Inference**

Full test statistic function with nuisance parameters  $\alpha$ :

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$$\underbrace{sum \text{ over processes}}_{c = S, B, \text{ etc.}}$$

$$\underbrace{p(x_i | \mu, \alpha)}_{Pref(x_i)} = \frac{1}{\sum_{c} G_{c}(\alpha) \cdot f_{c}(\mu) \cdot \nu_{c}} \sum_{c} \left[ f_{c}(\mu) \cdot g_{c}(x_i | \alpha) \cdot \nu_{c} \cdot \frac{p_{c}(x_i)}{p_{ref}(x_i)} \right]$$

$$\underbrace{x \sim p_{c}}_{S = 1}$$

$$\underbrace{x \sim p_{ref}}_{S = 0}$$

$$\underbrace{x \sim p_{ref}}_{S = 0}$$

$$\underbrace{r \sim p_{ref}}_{Cassification NN}$$

$$\underbrace{sum \text{ over processes}}_{Likelihood ratio trick^{*}}$$

$$\underbrace{r \sim hypothesis:}_{p_{c} \text{ and } p_{ref}}$$

$$\underbrace{r \sim p_{ref}}_{S = 0}$$

#### **Probability Calibration Test**

The NN ratios are meticulously trained to be true representations of the density ratios



Do the ratios capture the full un-biased dependence of the multi-dimensional feature space *x* ?



#### **Unblinded Results - Parameter scans**

#### Having validated the parameterized density ratios we build the test statistic scan for $\mu_{offshell}$



Neyman Construction, essential due to the non-linear parameterization, requires sampling pseudoexperiments from the PDF  $p(x | \mu, \alpha)$ , unlike histogram analysis which rely on Poisson bin-by-bin sampling.

Pseudo-experiments sampled using the newly developed techniques developed have been used to calculate the exact confidence intervals and background exclusion significance.



Two new papers from ATLAS open up the possibility of wide applications in ATLAS, CMS and beyond - potential to maximise the optimality of many analysis:

- Paper measuring the off-shell Higgs boson: [link]
- Paper with general method: [link]

Papers will be out soon, and current CONF note links will be replaced with paper links.

# Backup

## **Uncertainty Parameterization**

$$\frac{p(x_i | \mu, \alpha)}{p_{ref}(x_i)} = \frac{1}{\sum_c G_c(\alpha) \cdot f_c(\mu) \cdot \nu_c} \sum_c \left[ f_c(\mu) \cdot g_c(x_i | \alpha) \cdot \nu_c \cdot \frac{p_c(x_i)}{p_{ref}(x_i)} \right]$$
  
Factorized yield  $\alpha$ -dependence:  
$$G_c(\alpha) = \prod_k \frac{\nu_c(\alpha_k)}{\nu_c}$$
Per-event analog of standard techniques  
$$g_c(x | \alpha) = \prod_k \frac{p_c(x | \alpha_k)}{p_c(x)}$$

with  $\nu_c(\alpha_k)/\nu_c$  estimated using **analytic interpolation techniques:** 

Available from simulations  
at 
$$\alpha_k = 0$$
,  $\alpha_k^+$ ,  $\alpha_k^-$   

$$\frac{\nu_c(\alpha_k)}{\nu_c} = \begin{cases} \left(\frac{\nu_c(\alpha_k^+)}{\nu_c}\right)^{\alpha_k} & \alpha_k > 1 \\ 1 + \sum_{n=1}^6 c_n \alpha_k^n & -1 \le \alpha_k \le 1, \\ \left(\frac{\nu_c(\alpha_k^-)}{\nu_c}\right)^{-\alpha_k} & \alpha_k < -1 \end{cases}$$

with  $p_c(x \mid \alpha_k)/p_c(x)$  estimated using a mix of NNs and analytic interpolation techniques:

Density ratios trained using NNs from simulations at  $\alpha_r = 0$   $\alpha^+$   $\alpha_r^-$ 

$$\frac{\operatorname{at} \alpha_{k} = 0, \ \alpha_{k}^{+}, \ \alpha_{k}}{p_{c}(x \mid \alpha_{k})} = \begin{cases} \left( \underbrace{\frac{p_{c}(x \mid \alpha_{k}^{+})}{p_{c}(x)}} \right)^{\alpha_{k}} & \alpha_{k} > 1 \\ 1 + \sum_{n=1}^{6} c_{n} \alpha_{k}^{n} & -1 \le \alpha_{k} \le 1 \\ \left( \underbrace{\frac{p_{c}(x \mid \alpha_{k}^{-})}{p_{c}(x)}} \right)^{-\alpha_{k}} & \alpha_{k} < -1 \end{cases}$$

## **Impact of Systematic Uncertainties**

Table 5: Absolute systematic uncertainties on the measurement of  $\mu_{\text{off-shell}}$  in the  $H \rightarrow ZZ \rightarrow 4\ell$  decay channel. Two methods of estimation are presented: based on the variation of nuisance parameters and on the variation of global observables. Total uncertainties are given using the global observables methods since it allows variations to be summed in quadrature. The total uncertainty is independent of the method used to estimate systematic uncertainties.

Uncertainty source	Absolute impact on $\mu_{\text{off-shell}}$	
	Nuisance Parameter	Global Observable
Electron uncertainties	(-0.05, +0.06)	(-0.05, +0.06)
Muon uncertainties	(-0.03, +0.03)	(-0.02, +0.03)
Jet uncertainties	(-0.10, +0.10)	(-0.09, +0.11)
Luminosity	(-0.01, +0.01)	(-0.01, +0.01)
Total experimental	(-0.12, +0.13)	(-0.11, +0.12)
$q\bar{q} \rightarrow ZZ$ modeling	(-0.06, +0.07)	(-0.06, +0.07)
$gg \rightarrow ZZ$ modeling	(-0.08, +0.13)	(-0.07, +0.09)
EW $q\bar{q} \rightarrow ZZ + 2j$ modeling	(-0.01, +0.01)	(-0.01, +0.01)
Total modeling	(-0.10, +0.15)	(-0.09, +0.12)
Systematic uncertainty	(-0.16, +0.19)	(-0.14, +0.17)
Statistical uncertainty	(-0.49, +0.72)	(-0.50, +0.73)
Total uncertainty	(-0.54, +0.75)	

#### **Compatibility Tests**

# Testing the background exclusion sensitivity (in $\sigma$ )

	Expected	Observed
Bkg	1.3	2.5
Exclusion		

#### Testing the SM compatibility of $t_0^{obs}$ (in $\sigma$ )

	Observed
SM	1.26
compatibility	

p-value = 
$$\int_{t_0^{obs}}^{\infty} f(t_{\mu=0} \mid 1.0) = 0.11$$



Pseudo-experiments are sampled from the nominal ( $\mu = 1$ ) and bkg-only ( $\mu = 0$ ) hypothesis to set the bkg-exclusion limits and test the SM compatibility of the observed  $t_0$  result.

#### Where does the sensitivity come from? Not the tails



Figure 7: The sum of log density-ratios  $-2 \log(p(x_i|\mu')/p(x_i|\hat{\mu}))$  for events in bins of  $m_{4\ell}$ , for a hypothesis  $\mu' = 0.5$  (left) or a hypothesis  $\mu' = 1.5$  (right), with  $\hat{\mu} = 1$  as the maximum likelihood estimate on an Asimov dataset generated at  $\mu = 1$ . This represents the per-event contribution to the test statistic for a given hypothesis, as a function of  $m_{4\ell}$ . Events in regions with a sum greater than zero are collectively more consistent with a  $\mu = \mu'$  hypothesis over a  $\mu = \hat{\mu}$  hypothesis, while regions with a sum less than zero are collectively less consistent. The very high mass region  $(m_{4\ell} > 1000 \text{ GeV})$  is equally consistent with both hypotheses and provides no additional sensitivity.

#### **Parameterized Observables and Unbinning**



Figure 6: A comparison of expected sensitivity from various analysis strategies using the log-likelihood ratio test statistic  $t_{\mu}$ , as a function of  $\mu$ . The evaluation is performed on an Asimov dataset generated with  $\mu = 1$ . The red curve represents NSBI. The green curve represents a typical histogram analysis that uses a fixed observable,  $\log p_s/p(x|\mu = 1)$ , as a discriminant, with 15 bins. The markers show the sensitivity for various histogram analyses that use specific discriminants,  $p(x_i|\mu)/p(x_i|\mu = 1)$ , for specific values of  $\mu(= 0.0, 0.05, 0.15, 1.9)$ , with 15 (green pluses), 20 (yellow crosses), 30 (orange stars) or 90 (red dots) bins. The improved sensitivity of the green dots over the green curve (both using 15 bins) is due to the use of a parameterised observable.

#### Data/MC checks - NN outputs

We test the robustness of the multi-dimensional NN mapping by performing detailed data-MC validations



The NN output is also verified on data events from a orthogonal Control Region phase space, ensuring robustness of the mapping function.

#### **Data/MC checks - Optimality**

Following plots have data-MC comparisons with  $\mu = 0$  background-only histogram stacks. Red curves depict the distribution at best fit value  $\mu \sim 0.9$ 



The "optimal" observable at  $\mu = 0$